

# **2015 15th European Conference on Radiation and Its Effects on Components and Systems (RADECS 2015)**

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# RADECS 2015 Table of Contents

## Session A: Dose Effects in Devices and Integrated Circuits

<b>A-1</b>	<b>TID Impact on Process Modified CBRAM Cells .....</b>	1
	<i>Y. Gonzalez-Velo, A. Mahmud, W. Chen, J. Taggart, H. J. Barnaby, M. N. Kozicki, M. Ailavajhala, K. E. Holbert and M. Mitkova</i>	
<b>A-2</b>	<b>A 1 MGy TID Radiation-Tolerant 56 µW CMOS Temperature Sensor with ±1.7°C Accuracy.....</b>	5
	<i>Ying Cao, Jens Verbeeck, Marco Van Uffelen, Laura Mont Casellas, Carlo Damiani, Emilio Ruiz Morales, Roberto Ranz Santana, Richard Meek, Bernhard Haist, Wouter De Cock, Ludo Vermeeren, Michiel Steyaert and Paul Leroux</i>	
<b>A-3</b>	<b>SiGe HBT TCAD Simulation Taking into Account Impact of Proton Radiation .....</b>	9
	<i>Konstantin O. Petrosyants and Maxim V. Kozhukhov</i>	
<b>A-4</b>	<b>Total Ionizing Dose Effects in Carbon Nanotube Network Transistors .....</b>	13
	<i>Satoshi Ishii, Daisuke Yabe, Shigeki Koshio, Toshio Hirao, Shotaro Enomoto, Teruaki Konishi and Tsuyoshi Hamano</i>	
<b>PA-1</b>	<b>Dose Effects in CMOS Operational Amplifiers with Bipolar and CMOS Input Stage at Different Dose Rates and Temperatures .....</b>	16
	<i>Konstantin I. Tapero, Aleksandr S. Petrov, Pavel A. Chubunov, Victor N. Ulimov and Vasily S. Anashin</i>	
<b>PA-2</b>	<b>Evaluation of the Post-Irradiation Temperature Dependence of Operational Amplifier Input Bias Current.....</b>	20
	<i>Alexander S. Rodin, Alexander S. Bakerenkov, Viacheslav S. Pershenkov, Vladislav A. Felitsyn, Alina G. Miroshnichenko and Nikita S. Glukhov</i>	
<b>PA-3</b>	<b>Rad-Hard Versions of SPICE MOSFET Models for Effective Simulation of SOI/SOS CMOS Circuits Taking into Account Radiation Effects .....</b>	23
	<i>Konstantin O. Petrosyants, Igor A. Kharitonov, Lev M. Sambursky and Alexander S. Mokeev</i>	
<b>PA-4</b>	<b>TCAD Simulation of Total Ionization Dose Response of 45nm High-K MOSFETs on Bulk Silicon and SOI Substrate.....</b>	27
	<i>Konstantin O. Petrosyants and Dmitriy A. Popov</i>	
<b>PA-5</b>	<b>Flash-Based FPGA TID and Long-Term Retention Reliability through VT Shift Investigation.....</b>	31
	<i>Jih-Jong Wang, Nadia Rezzak, Durwyn Dsilva, Fengliang Xue, Salim Samiee, Pavan Singaraju, James Jia, Frank Hawley and Esmat Hamdy</i>	
<b>PA-6</b>	<b>Connection of the Parametric and Functional Control for TID Testing of Complex VLSI Circuits.....</b>	35
	<i>Vladimir A. Marfin, Pavel V. Nekrasov and Ilya O. Loskutov</i>	
<b>PA-7</b>	<b>Effect of Electron Irradiation on MISFET Integrated Hydrogen Sensors .....</b>	39
	<i>Boris I. Podlepetsky</i>	
<b>PA-8</b>	<b>The TID Effects of RRAM Based Oxide Material .....</b>	43
	<i>Yan Wang, Jinshun Bi, Jing Liu, Qi Liu, Hangbing Lv, Shibing Long and Ming Liu</i>	

<b>PA-9</b>	<b>The Impact of Plane-Polarized Unfocused Laser Radiation on Bulk Ionization in Deep-Submicron Modern ICs .....</b>	48
	<i>P. K. Skorobogatov, G. G. Davydov, A. V. Sogoyan, A. Y. Nikiforov and A. N. Egorov</i>	
<b>PA-10</b>	<b>Long-Term Transient Radiation Effects in SOI CMOS RF ICs.....</b>	52
	<i>Galina N. Nazarova, Vadim V. Elesin, George V. Chukov, Dmitry M. Amburkin and Alexander Y. Nikiforov</i>	
<b>PA-11</b>	<b>Influence of Neutrons Irradiation on Electrical Traps Existing in GaN-Based Transistors .....</b>	56
	<i>F. Berthet, S. Petididier, Y. Guhel, J. L. Trolet, P. Mary, C. Gaquière and B. Boudart</i>	

## **Session B: Basic Mechanisms of Radiation Effects**

<b>B-1</b>	<b>Radiation Vulnerability in 65 nm CMOS I/O Transistors after Exposure to Grad Dose .....</b>	60
	<i>Lili Ding, Simone Gerardin, Marta Bagatin, Serena Mattiazzo, Dario Bisello and Alessandro Paccagnella</i>	
<b>B-2</b>	<b>Physical Mechanisms of Radiation Response in Thick Isolation Oxides for Different Temperatures and Dose Rates .....</b>	65
	<i>M. G. Drosdetsky, G. I. Zebrev, A. M. Galimov and R. G. Useinov</i>	
<b>B-3</b>	<b>Modeling Charge Buildup in Deposited Oxides under X-Ray and Gamma Irradiation .....</b>	69
	<i>Anatoly A. Smolin, Armen V. Sogoyan, Anastasia V. Ulanova and Alexander A. Demidov</i>	
<b>PB-3</b>	<b>Application of Isotope Radiation Sources for Radiation Effects Simulation in Semiconductor Devices .....</b>	73
	<i>Erikh N. Vologdin, Fedor S. Pudovikov, Dmitry V. Sidorov and Vladimir F. Sinkevich</i>	

## **Session C: Hardness Assurance**

<b>C-1</b>	<b>Dose Rate Switching Technique to Estimate the Low Dose Rate Response of Bipolar Technologies.....</b>	76
	<i>J. Boch, A. Michez, M. Rousselet, S. Dhombres, L. Dusseau, E. Lorfèvre, N. Chatry, N. Sukhaseum and F. Saigné</i>	
<b>C-2</b>	<b>Comparison of Irradiation at Low Dose Rate and Irradiation at Elevated Temperature to Reveal ELDRS in Bipolar Linear Circuits.....</b>	80
	<i>Konstantin I. Tapero, Aleksandr S. Petrov, Pavel A. Chubunov, Victor N. Ulimov and Vasily S. Anashin</i>	
<b>C-3</b>	<b>Method of SEU-Hardness Assurance for SRAM with Error Correction Using Focused Laser Sources.....</b>	85
	<i>Anna B. Boruzdina, Alexander A. Pechenkin, Igor B. Yashanin, Anastasiya V. Ulanova, Andrey V. Yanenko and Alexander I. Chumakov</i>	
<b>PC-1</b>	<b>The Issue of Using Test Dose Rate 10 mrad(Si)/s for ELDRS Prediction in MIL-STD-883-H .....</b>	88
	<i>Alexander T. Yastrebov, Viacheslav S. Pershenkov, Alexander S. Bakerenkov, Vladislav A. Felitsyn, Alexander S. Rodin, Vladimir V. Belyakov and Vladimir V. Shurenkov</i>	
<b>PC-2</b>	<b>Experimental Technique for Determination of ELDRS-Free Devices.....</b>	91
	<i>Vasily S. Anashin, Viacheslav S. Pershenkov, Alexander S. Bakerenkov, Pavel A. Chubunov, Anatoly V. Solomatin, Alexander S. Rodin and Vladislav A. Felitsyn</i>	

<b>PC-3</b>	<b>The Technique for Estimation of the Chip Temperature of Integrated Circuits during Irradiation.....</b>	95
	<i>Vladislav A. Felitsyn, Alexander S. Bakerenkov, Viacheslav S. Pershenkov, Alexander S. Rodin, Vladimir V. Belyakov, Vladimir V. Shurenkov and Nikita S. Glukhov</i>	
<b>PC-4L</b>	<b>The Effectiveness of Specialized IC Packages: Experimental and Monte-Carlo Simulation for Basic Orbits and Spacecraft Shielding .....</b>	99
	<i>Alexey O. Akhmetov, Georgy S. Sorokoumov, Dmitry V. Bobrovsky, Dmitry V. Boychenko, Alexander Y. Nikiforov, Alexander I. Chumakov, Jean-Charles Thomas, Aleksei U. Maksimov and Nikolay A. Vasilenko</i>	

## Session D: Single Event Effects in Devices & Integrated Circuits

<b>D-1</b>	<b>CARMEN1 and CARMEN2 Experiment: Comparison between In-Flight Measured SEE Rates and Predictions .....</b>	104
	<i>A. Samaras, A. Varotsou, N. Chatry, E. Lorfrevre, F. Bezerra and R. Ecoffet</i>	
<b>D-2</b>	<b>Experimental Characterization and In-Flight Observation of Weakened Cell in SDRAM .....</b>	110
	<i>A. Samaras, B. Vandevelde, N. Sukhaseum, N. Chatry, A. Rodriguez, F. Wrobel, F. Bezerra, E. Lorfrevre and R. Ecoffet</i>	
<b>D-3</b>	<b>Heavy-Ion Radiation Impact on a 4Mb FRAM under Different Test Conditions.....</b>	118
	<i>V. Gupta, A. Bosser, G. Tsiliogiannis, A. Zadeh, A. Javanainen, A. Virtanen, H. Puchner, F. Saigné, F. Wrobel and L. Dilillo</i>	
<b>D-4</b>	<b>Reliability Analysis of Operating Systems for Embedded SoC.....</b>	121
	<i>Thiago Santini, Luigi Carro, Flávio Rech Wagner and Paolo Rech</i>	
<b>PD-1</b>	<b>On the Characterization of Embedded Memories of Zynq-7000 All Programmable SoC under Single Event Upsets Induced by Heavy Ions and Protons .....</b>	126
	<i>Lucas Antunes Tambara, Alexey Akhmetov, Dmitry V. Bobrovsky and Fernanda Lima Kastensmidt</i>	
<b>PD-2</b>	<b>Analyzing the Failure Impact of Using Hard- and Soft-Cores in All Programmable SoC under Neutron-Induced Upsets.....</b>	130
	<i>Lucas Antunes Tambara, Paolo Rech, Eduardo Chielle and Fernanda Lima Kastensmidt</i>	
<b>PD-3</b>	<b>Sensitivity to Neutron Radiation of a 45 nm SOI Multi-Core Processor .....</b>	135
	<i>Pablo Ramos, Vanessa Vargas, Maud Baylac, Francesca Villa, Solenne Rey, Juan Antonio Clemente, Nacer-Eddine Zergainoh and Raoul Velasco</i>	
<b>PD-4</b>	<b>Investigation of Single Event Functional Interrupts in Microcontroller with PIC17 Architecture .....</b>	139
	<i>Pavel V. Nekrasov, Andrey B. Karakozov, Dmitry V. Bobrovskyi and Vladimir A. Marfin</i>	
<b>PD-5</b>	<b>A Methodology for the Analysis of Memory Response to Radiation through Bitmap Superposition and Slicing .....</b>	143
	<i>A. Bosser, V. Gupta, G. Tsiliogiannis, R. Ferraro, C. Frost, A. Javanainen, H. Puchner, M. Rossi, F. Saigné, A. Virtanen, F. Wrobel, A. Zadeh and L. Dilillo</i>	
<b>PD-6</b>	<b>Nonuniform Optical Losses in Laser SEE Tests .....</b>	147
	<i>Dmitry V. Savchenkov, Alexander I. Chumakov, Oleg V. Merkushin, Georgy G. Davydov and Vladimir A. Marfin</i>	

<b>PD-7</b>	<b>SEE Laser Testing at Different Temperatures.....</b>	151
	<i>Alexander A. Novikov, Alexander A. Pechenkin, Alexander I. Chumakov, Alexey O. Akhmetov and Oleg B. Mavritskii</i>	
<b>PD-8</b>	<b>Investigation of SEGR Cross-Section in Power MOSFETs under Proton Irradiation .....</b>	154
	<i>Evgenij V. Mitin and Valery G. Malinin</i>	
<b>PD-9</b>	<b>Experimental Study of 0.18μm and 65nm SRAM SEUs Induced by Heavy Ions, High Energy Protons and Low Energy Protons on Orbits .....</b>	157
	<i>Qingkui Yu, Lei Luo, Min Tang, Yi Sun, Zhichao Wei, Zheng Li and Ming Zhu</i>	
<b>PD1L</b>	<b>Neutron-Induced Single Events in a COTS Soft-Error Free SRAM at Low Bias Voltage.....</b>	162
	<i>Juan A. Clemente, Francisco J. Franco, Francesca Villa, Maud Baylac, Pablo Ramos, Vanessa Vargas, Hortensia Mecha, Juan A. Agapito and Raoul Velasco</i>	
<b>PD2L</b>	<b>Analysis and Detection of Multiple Cell Upsets in SRAM Memories Used as Particle Detectors .....</b>	166
	<i>R. Seconde, G. Foucard, S. Danzeca, R. Losito, P. Peronnard, A. Masi, M. Brugger and L. Dusseau</i>	
<b>PD3L</b>	<b>Multiple Cell Upset Mechanisms in SRAMs .....</b>	170
	<i>Alexander I. Chumakov, Armen V. Sogoyan, Anna B. Boruzdina, Anatoly A. Smolin and Alexander A. Pechenkin</i>	

## Session E: Radiation Environments

<b>E-1</b>	<b>Simulation and Optimization for Space Low Energy Charged Particle Detector .....</b>	175
	<i>De-dong Ba and Feng Shi</i>	
<b>E-2</b>	<b>Comparison of the Models of Charged Particle Fluxes in Space .....</b>	178
	<i>N. V. Kuznetsov, N. I. Nikolaeva, R. A. Nyymik, V. M. Uzhegov, M. V. Yakovlev and M. I. Panasyuk</i>	
<b>E-3</b>	<b>Correction of In-Flight Dose Sensors Measurements Results in a Middle-Earth Orbit Taking the Fading Effect into Account .....</b>	182
	<i>Vasily S. Anashin, Grigory A. Protopopov, Olga S. Kozyukova, Igor A. Lyakhov, Sergey V. Balashov, Ninel N. Sitnikova, Sergey V. Tasenko, Pavel V. Shatov and Viktor D. Popov</i>	
<b>PE-2</b>	<b>Monte Carlo Tools Accuracy for High Energetic Electron Radiation Environment .....</b>	186
	<i>J. Cueto, S. Ibarmia, P. Calvel, G. Eiguren, J. Eck, V. Ivanchenko and G. Santin</i>	
<b>PE-3L</b>	<b>Features of Radiation Environment Calculation for Spacecrafts Flying on Complex Orbit .....</b>	190
	<i>M. Artiomov and N. Khamidullina</i>	

## Session F: Single Event Transients

<b>F-1</b>	<b>Measurement and Analysis of Multiple Output Transient Propagation in BJT Analog Circuits.....</b>	194
	<i>Nicolas J.-H. Roche, A. Khachatrian, J. H. Warner, S. P. Buchner, D. McMorrow and D. Clymer</i>	
<b>F-2</b>	<b>UV Single-Photon Absorption Single-Event Transient Testing of Pristine and Irradiated AlGaN/GaN HEMTs .....</b>	198
	<i>Ani Khachatrian, Nicolas J.-H. Roche, Stephen P. Buchner, Andrew D. Koehler, Jordan D. Greenlee, Travis J. Anderson, Jeffrey H. Warner and Dale McMorrow</i>	

<b>PF-1</b>	<b>Simulation of Proton Induced SET in Linear Devices and Assessment of Sensitive Thicknesses .....</b>	202
	<i>Cecile Weulersse, Sébastien Morand, Florent Miller, Thierry Carrière and Renaud Mangeret</i>	
<b>PF-2</b>	<b>Measurement of SET Injected Charge from a Californium-252 Source in 340 nm Straight and Enclosed Layout NMOS and PMOS Transistors .....</b>	206
	<i>D. Englisch, M. Horstmann, S. Athanasiou, R. J. E. Jansen and B. Glass</i>	
<b>PF-3</b>	<b>Impact of Radiation-Induced Single-Event Transients on High Resolution Time to Digital Converter .....</b>	210
	<i>S. Balaji and S. Ramasamy</i>	

## Session G: Photonics and Optoelectronics Devices

<b>G-1</b>	<b>Dark Current Spectroscopy on Alpha Irradiated CMOS Image Sensors .....</b>	215
	<i>Jean-Marc Belloir, Vincent Goiffon, Cédric Virmontois, Mélanie Raine, Philippe Paillet, Pierre Magnan and Olivier Gilard</i>	
<b>G-2</b>	<b>Dose Effects on CMOS Active Pixel Sensors.....</b>	219
	<i>S. Dhombres, A. Michez, J. Boch, S. Beauvivre, J. -R. Vaillé, A. D. Touboul, P. C. Adell, F. Bezerra, E. Lorfèvre, D. Kraehenbuehl and F. Saigné</i>	
<b>G-3</b>	<b>Investigation of Nonuniform Degradation of CMOS-Sensor Light-Sensitive Surface under Gamma-Irradiation .....</b>	222
	<i>Maksim E. Cherniak, Anatoly A. Smolin, Anastasiya V. Ulanova and Alexander Y. Nikiforov</i>	
<b>G-4</b>	<b>Proton Irradiation Effects on Commercial Laser Diodes.....</b>	225
	<i>Giulia Marcello, Giovanna Mura, Massimo Vanzi, Marta Bagatin, Simone Gerardin and Alessandro Paccagnella</i>	
<b>G-5</b>	<b>Cerium Codoping Effect on the Radiation Response of Germanosilicate and Phosphosilicate Multimode Optical Fibers.....</b>	229
	<i>D. Di Francesca, S. Girard, S. Agnello, A. Alessi, C. Marcandella, P. Paillet, N. Richard, A. Boukenter, Y. Ouerdane and F. M. Gelardi</i>	
<b>G-6</b>	<b>Radiation Induced Attenuation Kinetics in Pure-Silica-Core Optical Fibers during Successive Irradiations .....</b>	233
	<i>A. Alessi, S. Girard, D. Di Francesca, C. Marcandella, P. Paillet, A. Boukenter and Y. Ouerdane</i>	
<b>G-7</b>	<b>Radiation Response of OFDR Distributed Sensors Based on Microstructured Pure Silica Optical Fibers .....</b>	237
	<i>S. Rizzolo, A. Boukenter, J. Périsse, G. Bouwmans, H. El Hamzaoui, L. Bigot, Y. Ouerdane, M. Cannas, M. Bouazaoui, J.-R. Macé, S. Bauer and S. Girard</i>	
<b>PG-1</b>	<b>Performance Degradation after Proton Irradiation in Charge-Coupled Devices: A Cross-Device Comparison.....</b>	240
	<i>Thibaut Prod'homme, Peter Verhoeve, Thierry Beaufort, Sander Bloammert, Bart Butler, Ludovic Duvet, Frederic Lemmel, Hans Smit and Cornelis van der Luijt</i>	
<b>PG-2</b>	<b>Total Ionizing Dose and Displacement Damage Effects in a Tunable Laser Diode Based Fiber Optic Sensing System .....</b>	245
	<i>Markus Roner, Philipp Putzer, Andreas Hurni, Sebastian Schweyer and Norbert M. K. Lemke</i>	

<b>PG-3</b>	<b>Impact of the Border Crossing Effects on the DCNU for Pixels Arrays Irradiated with High Energy Protons.....</b>	250
	<i>M. C. Ursule, C. Inguimbert and T. Nuns</i>	
<b>PG-4</b>	<b>Raman Based Distributed Fiber Optic Temperature Sensors for Structural Health Monitoring in Radiation Environment.....</b>	256
	<i>C. Cangialosi, S. Girard, M. Cannas, A. Boukenter, E. Marin, S. Delepine-Lesoille, C. Marcandella, P. Paillet and Y. Ourdane</i>	
<b>PG-5</b>	<b>Distributed Optical Fiber Radiation Sensing at CERN High Energy AcceleRator Mixed Field Facility (CHARM).....</b>	259
	<i>I. Toccafondo, A. Thornton, E. Guillermain, J. Kuhnhenn, J. Mekki, M. Brugger and F. Di Pasquale</i>	
<b>PG-6</b>	<b>The Influence of the 21 MeV Protons on Heterolaser Optical Capacity Based on Gallium-Arsenide with Fiber Resonator.....</b>	263
	<i>V. V. Alekseev, I. I. Dolgov, P. I. Dolgov, A. V. Ivanov, V. M. Isaev, V. T. Semenov, V. D. Kurnosov and M. V. Kozhukhov</i>	
<b>PG-7</b>	<b>Kinetics of Radiation -Induced Optical Losses in Undoped Fiber for Different Temperatures: Experiment and Modeling.....</b>	267
	<i>Rustem G. Useinov and Ivan I. Dolgov</i>	
<b>PG-8</b>	<b>Dose-Rate Dependence of Fiber Bragg Gratings' Responses .....</b>	271
	<i>Adriana Morana, Emmanuel Marin, Sylvain Girard, Claude Marcandella, Philippe Paillet, Aziz Boukenter and Youcef Ouerdane</i>	
<b>PG-9L</b>	<b>Multiscale Modeling of Accumulation of Radiation Defects in Silicon Detectors under Alpha Particle Irradiation .....</b>	274
	<i>Mikhail Yu. Romashka, Alexey V. Yanilkin, Alexander I. Titov, Dmitry V. Gusin, Alexey V. Sidelev and Dmitry Yu. Mokeev</i>	

## Session H: Facilities and Dosimetry

<b>H-1</b>	<b>Using the FLNR Accelerator Complex for SEE Testing: State of Art and Future Development.....</b>	278
	<i>Igor V. Kalagin, Georgy G. Gulbekyan, Boris N. Gikal, Semen V. Mitrofanov, Vladimir A. Skuratov, Yuri G. Teterov and Vasily S. Anashin</i>	
<b>H-2</b>	<b>A Mixed Field Facility at CERN for Radiation Test: CHARM.....</b>	284
	<i>J. Mekki, M. Brugger, R. G. Alia, A. Thornton, N. C. Dos Santos Mota and S. Danzeca</i>	
<b>H-3</b>	<b>ISNP/GNEIS Facility in Gatchina for Neutron Testing with Atmospheric-Like Spectrum .....</b>	288
	<i>Oleg A. Shcherbakov, Alexander S. Vorobyev, Alexei M. Gagarski, Larisa A. Vaishnene, Evgeni M. Ivanov, Vasily S. Anashin, Linalis R. Bakirov and Aleksandr E. Koziukov</i>	
<b>H-4</b>	<b>Comparison of a Readout Chain Dedicated to the Signal Conditioning of a Particle Detector and an Innovative Chain Based on a VCO Concept.....</b>	291
	<i>S. Ben Krit, K. Coulié-Castellani, W. Rahajandraibe, L. Ottaviani, G. Micolau, H. Aziza and J.-M. Portal</i>	
<b>H-5</b>	<b>Optimization of Flexible Ag-Chalcogenide Glass Sensors for Radiation Detection .....</b>	296
	<i>A. Mahmud, Y. Gonzalez-Velo, M. Saremi, H. J. Barnaby, M. N. Kozicki, K. E. Holbert, M. Mitkova, T. L. Alford, M. Goryll, D. Mahalanabis, W. Yu, W. Chen and J. Taggart</i>	

<b>PH-1</b>	<b>High Energy (20-60 AMeV) Ion Beam-Line for SEE Testing at U400M FLNR JINR Cyclotron.....</b>	300
	<i>S. L. Bogomolov, G. G. Gulbekyan, V. A. Skuratov, I. V. Kalagin, S. V. Mitrofanov, Yu. G. Teterov, A. S. Fomichev and V. S. Anashin</i>	
<b>PH-2</b>	<b>The "Livio Scarsi" X-Ray Facility at University of Palermo for Device Testing .....</b>	305
	<i>F. Principato, G. Gerardi, A. A. Turturici, G. Raso, M. Quartararo, F. Pintacuda and L. Abbene</i>	
<b>PH-3</b>	<b>Grenoble Large Scale Facilities for Advanced Characterisation of Microelectronics Devices .....</b>	312
	<i>J. Beaucour, J. Segura-Ruiz, B. Giroud, E. Capria, E. Mitchell, C. Curfs, J. C. Royer, M. Baylac, F. Villa and S. Rey</i>	
<b>PH-4</b>	<b>Small-Size High-Performance ARSA Accelerators for On-Line Testing for ECB Radiation Hardness .....</b>	316
	<i>Svetlana L. Elyash, Sergei P. Pukhov, Anatolii V. Rodigin and Andrei L. Yuryev</i>	
<b>PH-5</b>	<b>Dosimetry Inter-Laboratory Comparison between ESTEC, CNA-ALTER/RADLAB, and UCL.....</b>	320
	<i>Alessandra Costantino, Michele Muschitiello, Ali Zadeh, Gonzalo Fernandez Romero, Pedro Martín Holgado, Yolanda Morilla, Gema Muñiz, Laurent Standaert and Julien Vanhees</i>	
<b>PH-6</b>	<b>Detailed Geant4 Simulations of the ANITA and ANITA-CUP Neutron Facilities .....</b>	328
	<i>Q. Hong, S. P. Platt, A. V. Prokofiev and E. Passoth</i>	
<b>PH-7</b>	<b>A Fast Neutron Detector Using 10B-Lined Ionization Chamber for Mixed Field Dosimetry.....</b>	332
	<i>Zixia Zhang, Zhiyong Wei, Meihua Fang, Li Zhu, Guoyun Chen, Peng Qiang and Qin Ni</i>	
<b>PH-9L</b>	<b>Magnetic Buncher Accelerator for Radiation Hardness Research and Pulse Detector Characterization .....</b>	336
	<i>Yuri S. Pavlov and Petr B. Lagov</i>	

## Radiation Effects Data Workshop

<b>DW-1</b>	<b>Total Dose and SEE Testing of the Intersil ISL75052SEH Low Dropout Regulator .....</b>	339
	<i>N. W. van Vronno, J. S. Gill, L. G. Pearce, C. Boucheron and E. J. Thomson</i>	
<b>DW-2</b>	<b>TID Response of Various Field Programmable Gate Arrays and Memory Devices.....</b>	345
	<i>J. M. Armani, J. L. Leray, R. Gaillard and V. Iluta</i>	
<b>DW-4</b>	<b>Enhanced Low Dose Rate Sensitivity Analysis of Vertical BJT-STMicroelectronics .....</b>	349
	<i>Francesco Pintacuda, Marc Poizat and Michele Muschitiello</i>	
<b>DW-6</b>	<b>SEL Sensitivity Differences in ICs with Same Crystals Marking .....</b>	353
	<i>Alexander A. Pechenkin, Pavel V. Nekrasov, Anna B. Boruzdina and Dmitry E. Protasov</i>	
<b>DW-7</b>	<b>Different Chips at Identical Marking on the Example of OP1177.....</b>	357
	<i>Alexandra V. Demidova, Alexander A. Pechenkin, Alexey Y. Borisov, Leonid N. Kessarinskiy, Andrey V. Yanenko, Dmitry V. Boychenko and Alexander Y. Nikiforov</i>	
<b>DW-8</b>	<b>Identification of Authenticity of Microelectronic Devices Using Radiation Simulation Modeling .....</b>	360
	<i>D. V. Boychenko, A. Yu. Nikiforov, Yu. A. Ozhegin, T. A. Kondratyeva and V. A. Telets</i>	
<b>DW-9</b>	<b>The Critical Elements of the Modern Transceiver ICs upon Space Radiation Exposure .....</b>	363
	<i>G. G. Davydov, A. S. Kolosova, D. V. Boychenko and A. A. Pechenkin</i>	

<b>DW-10</b>	<b>Total Ionizing Dose Effects in Phase-Locked Loop ICs and Frequency Synthesizers .....</b>	367
	<i>Denis I. Sotskov, Vadim V. Elesin, Aleksander G. Kuznetsov, Galina N. Nazarova, George V. Chukov, Dmitry V. Boychenko, Vitaliy A. Telets and Nikolay A. Usachev</i>	
<b>DW-11</b>	<b>The Features of Radiation-Hardening-By-Design of Bulk SRAM Cells.....</b>	370
	<i>Yuriy M. Gerasimov, Nikolay G. Grigoryev, Andrey V. Kobilyatskiy, Yaroslav Ya. Petrichkovich and Tatiana V. Solokhina</i>	
<b>DW-12</b>	<b>Design and SEE Testing of High Density High Speed Radhard Synchronous SRAM .....</b>	374
	<i>Vasily S. Anashin, Pavel A. Chubunov, Grigory A. Protopopov, Sergey A. Iakovlev, Aleksey V. Perebeynos, Aleksander V. Rutkevich, Dmitriy I. Voronkov, Yaroslav S. Gubin, Boris A. Novikov, Dmitriy A. Skaryukin and Aleksandra S. Popova</i>	
<b>DW-13</b>	<b>SEE Test Results of 256k RAM with Preliminary TID Irradiation .....</b>	378
	<i>Vasily S. Anashin, Pavel A. Chubunov and Sergey A. Iakovlev</i>	
<b>DW-14</b>	<b>Typical Facilities and Procedure for Single Event Effects Testing in Roscosmos.....</b>	382
	<i>Vasily S. Anashin, Pavel A. Chubunov, Sergey A. Iakovlev, Aleksandr E. Koziukov, Georgiy G. Gulbekyan, Vladimir A. Skuratov and Semen V. Mitrofanov</i>	
<b>DW-15</b>	<b>Analysis Results of In-Flight Measurements in Geostationary and Polar Orbits in 2014-2015 .....</b>	388
	<i>Vasily S. Anashin, Grigory A. Protopopov, Pavel V. Shatov, Sergey V. Tasenko, Viktor D. Popov, Olga S. Kozyukova and Igor A. Lyakhov</i>	
<b>DW-16</b>	<b>TID and SEGR Radiation Characterisation of European COTS Power MOSFETs with Respect to Space Application Electronics .....</b>	391
	<i>Michael Wind, Jayasimha V. Bagalkote, Peter Beck, Marcin Latocha and Marc Poizat</i>	
<b>DW-17</b>	<b>X-Ray-Induced Upsets in a Xilinx Spartan 3E FPGA .....</b>	394
	<i>Marcilei A. G. da Silveira, Roberto B. B. Santos, Felipe G. H. Leite, Nicolas E. Araújo, Nilberto H. Medina, Bruno C. Porcher, Vitor A. P. Aguiar, Nemitala Added and Fabian Vargas</i>	
<b>DW-18</b>	<b>Radiation Tolerance of Programmable Voltage Supply and High Galvanic Insulation Readout Electronics Used by CERN's LHC Cryogenics.....</b>	398
	<i>J. Casas, N. Trikoupis and J. Mekki</i>	
<b>DW-19</b>	<b>MGy Radiation Assessment of a Space-Graded Amplifier and ADC .....</b>	403
	<i>Ying Cao, Jens Verbeeck, Marco Van Uffelen, Laura Mont Casellas, Carlo Damiani, Emilio Ruiz Morales, Roberto Ranz Santana, Richard Meek, Bernhard Haist, Wouter De Cock, Ludo Vermeeren, Michiel Steyaert and Paul Leroux</i>	
<b>DW-22L</b>	<b>Radiation-Hardened Gate Array with Embedded SRAM .....</b>	406
	<i>N. Malashevich, M. Makarceva and R. Fedorov</i>	

## Session I: Hardening by Technology, Design and System

<b>I-1</b>	<b>A Radiation-Hardened Non-Redundant Flip-Flop, Stacked Leveling Critical Charge Flip-Flop in a 65 nm Thin BOX FD-SOI Process .....</b>	410
	<i>Junki Yamaguchi, Jun Furuta and Kazutoshi Kobayashi</i>	

I-2	<b>A MGy, Low-Offset Programmable Instrumentation Amplifier IC for Nuclear Applications.....</b>	414
	<i>Jens Verbeeck, Ying Cao, Marco Van Uffelen, Laura Mont Casellas, Carlo Damiani, Emilio Ruiz Morales, Roberto Ranz Santana, Richard Meek, Bernhard Haist, Wouter De Cock, Ludo Vermeeren, Michiel Steyaert and Paul Leroux</i>	
I-3	<b>Partial TMR in FPGAs Using Approximate Logic Circuits .....</b>	418
	<i>A. Sánchez-Clemente, L. Entrena and M. García-Valderas</i>	
I-4	<b>Redundant Skewed Clocking of Pulse-Clocked Latches for Low Power Soft Error Mitigation .....</b>	422
	<i>Aditya Gujja, Srivatsan Chellappa, Chandrasekaran Ramamurthy and Lawrence T. Clark</i>	
I-5	<b>Validation of FDIR Strategy for Spaceborne SRAM-Based FPGAs Using Proton Radiation Testing .....</b>	429
	<i>Felix Siegle, Tanya Vladimirova, Christian Poivey and Omar Emam</i>	
I-6	<b>Architectural and Micro-Architectural Techniques for Software Controlled Microprocessor Soft-Error Mitigation .....</b>	437
	<i>Anudeep R. Gogulamudi, Lawrence T. Clark, Chad Farnsworth, Srivatsan Chellappa and Vinay Vashishtha</i>	
I-7	<b>Reliability on ARM Processors against Soft Errors by a Purely Software Approach.....</b>	443
	<i>Eduardo Chielle, Felipe Rosa, Gennaro S. Rodrigues, Lucas A. Tambara, Fernanda L. Kastensmidt, Ricardo Reis and Sergio Cuenca-Asensi</i>	
PI-2	<b>Physical Design Methodologies for Soft Error Mitigation Using Redundancy .....</b>	448
	<i>Chandrasekaran Ramamurthy, Srivatsan Chellappa and Lawrence T. Clark</i>	
PI-3	<b>A Family of Rad-Hard ADC with Flash Architecture .....</b>	453
	<i>Umberto Gatti and Cristiano Calligaro</i>	
PI-4	<b>Semi-Empirical Method for Estimation of Single-Event Upset Cross-Section for SRAM DICE Cells .....</b>	458
	<i>Maxim S. Gorbunov, Anna B. Boruzdina and Pavel S. Dolotov</i>	
PI-5	<b>The Experimental and Simulation Study of Specialized Thermal Control Coating Application for Radiation Shielding of Electronic Components .....</b>	462
	<i>Vasily S. Anashin, Grigory A. Protopopov, Olga S. Kozyukova, Igor A. Lyakhov, Vladimir F. Zinchenko, Anatoly V. Grigorevskiy, Rashid H. Khasanshin and Armen V. Sogyan</i>	
PI-6	<b>The Experimental and Simulation Study of Radiation Shielding Properties of Multilayer Shielding Cases with Tantalum Carbide Extender Pigment.....</b>	466
	<i>Vasily S. Anashin, Grigory A. Protopopov, Olga S. Kozyukova, Anatoly V. Grigorevskiy, Larisa V. Kiseleva, Sergey V. Tokar, Igor A. Lyakhov, Pavel A. Chubunov and Aleksey V. Perebeynos</i>	
PI-7	<b>The Radiation-Hardened Differential Stages and Op Amps without Classical Reference Current Source .....</b>	469
	<i>N. N. Prokopenko, O. V. Dvornikov, I. V. Pakhomov and N. V. Butyrugin</i>	
PI-8	<b>Verifying Hardening Techniques for Distributed Electronic Systems in Critical Applications .....</b>	473
	<i>A. Vaskova, C. López-Ongil, M. García-Valderas, M. Portela-García, Y. Morilla and Gema Muñiz</i>	
PI-9L	<b>Elimination of Single Event Latch-Up in the ATMEL ATMIX150RHA Rad-Hard CMOS 150nm Cell-Based ASIC Family .....</b>	478
	<i>D. Truyen, E. Leduc and F. Braud</i>	

## Session J: Single Event Effects Mechanisms and Modeling

J-1	<b>New Insight into Heavy Ion Induced SEGR: Impact of Charge Yield.....</b>	481
	<i>Vladimir V. Emelyanov, Alexander S. Vatuev and Rustem G. Useinov</i>	
J-2	<b>Analysis of BOX Layer Thickness on SERs of 65 and 28nm FD-SOI Processes by a Monte-Carlo Based Simulation Tool .....</b>	485
	<i>Kuiyuan Zhang, Shohei Kanda, Junki Yamaguchi, Jun Furuta and Kazutoshi Kobayashi</i>	
J-3	<b>Proton-Induced SDRAM Cell Degradation .....</b>	490
	<i>A. Rodriguez, F. Wrobel, A. Samaras, F. Bezerra, B. Vandevelde, R. Ecoffet, A. Touboul, N. Chatry, L. Dilillo and F. Saigné</i>	
J-4	<b>Analysis of SRAM-Based FPGA SEU Sensitivity to Combined Effects of Conducted EMI and TID .....</b>	494
	<i>Juliano Benfica, Bruno Green, Bruno C. Porcher, Letícia Bolzani Poehls, Fabian Vargas, Nilberto H. Medina, Nemitala Added, Vitor A. P. de Aguiar, Eduardo L. A. Macchione, Fernando Aguirre, Marcilei A. G. da Silveira and Eduardo A. Bezerra</i>	
PJ-1	<b>Multiple Cell Upset Cross-Section Uncertainty in Nanoscale Memories: Microdosimetric Approach .....</b>	498
	<i>G. I. Zebrev, K. S. Zemtsov, R. G. Useinov, M. S. Gorbunov, V. V. Emelyanov and A. I. Ozerov</i>	
PJ-2	<b>Body Bias Effects on the Single-Event-Transient Response of PDSOI Devices.....</b>	503
	<i>Jinshun Bi, Li Chen, Zhengsheng Han, Yan Wang and Ming Liu</i>	
PJ1L	<b>Statistical Anomalies of Bitflips in SRAMs to Discriminate MCUs from SEUs.....</b>	507
	<i>Juan Antonio Clemente, Francisco J. Franco, Francesca Villa, Maud Baylac, Solenne Rey, Hortensia Mecha, Juan A. Agapito, Helmut Puchner, Guillaume Hubert and Raoul Velasco</i>	
PJ2L	<b>Modified Charge Collection Model by Point Node for SEE Sensitivity Estimation .....</b>	511
	<i>Alexander I. Chumakov</i>	
	<b>Author Index.....</b>	516